A Complete Bibliography of Publications in *Technometrics* for the decade 2000–2009

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Title word cross-reference

1 [OH05]. 12 [MS01]. 2^{k-p} [BH00, LM02, MP00]. 2^{m-p} [KT03]. **$69.95** [Zie01-52]. 80^{th} [Gho07]. C_P [Mal00]. D [GV03, Mit00]. $E(s^2)$ [NC08]. F [Ano00e, SBD98]. g [FG06]. h [FG06]. K [SC04, CFP08, LD04]. m [BG06]. μ [BGD05]. n [CFP08]. p [BG06, MW05]. r [BG06]. T^2 [CJFR05].

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3 [Zie00m]. **3rd** [Ano09g, Ano09b, Ano09f, Boo09a, Lip09].

4 [Zie00-44]. **43** [IM02]. **48** [Bri06, Buj06, Efr06, Hub06, Lan06]. **4th** [Bar09, Hor09c].

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